

October 2010
UniFET-II<sup>TM</sup>

## FDP12N50NZ / FDPF12N50NZ

# **N-Channel MOSFET**

500V, 11.5A, 0.52 $\Omega$ 

#### **Features**

- $R_{DS(on)} = 0.46\Omega$  ( Typ. ) @  $V_{GS} = 10V$ ,  $I_D = 5.75A$
- Low gate charge (Typ. 23nC)
- Low C<sub>rss</sub> ( Typ. 14pF )
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS compliant

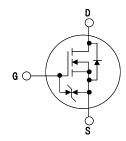
## **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.







## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter		FDP12N50NZ	FDPF12N50NZ	Units	
V <sub>DSS</sub>	Drain to Source Voltage			5	500	V	
$V_{GSS}$	Gate to Source Voltage			±25		V	
	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		11.5	11.5*		
ID	Drain Current	- Continuous (T <sub>C</sub> = 100°C)		6.9	6.9*	Α	
I <sub>DM</sub>	Drain Current	- Pulsed (Note 1) 46 46*		Α			
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 2)	560		mJ	
I <sub>AR</sub>	Avalanche Current		(Note 1)	11.5		Α	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		17		mJ		
dv/dt	Peak Diode Recovery dv/	/dt	(Note 3)	4	4.5	V/ns	
<b>D</b>	Dawer Dissipation	$(T_C = 25^{\circ}C)$		170	42	W	
$P_{D}$	Power Dissipation	- Derate above 25°C		1.37	0.33	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Te	erating and Storage Temperature Range		-55 t	o +150	οС	
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			3	300	°C	

\*Dran current limited by maximum junction temperature

#### Thermal Characteristics

Symbol	Parameter	FDP12N50NZ	FDPF12N50NZ	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.73	3.0	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP12N50NZ	FDP12N50NZ	TO-220	-	-	50
FDPF12N50NZ	FDPF12N50NZ	TO-220F	=	=	50

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	eteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ}C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.5	-	V/°C
1	Zero Gate Voltage Drain Current	$V_{DS} = 500V, V_{GS} = 0V$	-	-	1	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 400V, T_{C} = 125^{\circ}C$	-	-	10	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$	-	-	±10	μΑ

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 5.75A$	-	0.46	0.52	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20V, I_{D} = 5.75A$	-	12	ı	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V f = 1MHz	-	945	1235	pF
C <sub>oss</sub>	Output Capacitance		-	155	205	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	-	14	20	pF
$Q_g$	Total Gate Charge at 10V	V 400V L 44.5A	-	23	30	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 11.5A$ $V_{GS} = 10V$	-	5.5	-	nC
Q <sub>qd</sub>	Gate to Drain "Miller" Charge	VGS = 10 V	-	9.6	-	nC

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	20	50	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 250V, I_D = 11.5A$	-	50	110	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25\Omega$	-	60	130	ns
t <sub>f</sub>	Turn-Off Fall Time		-	45	100	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	11.5	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	46	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 11.5A$	-	-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 11.5A	-	315	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	2.0	-	μС

#### Notes

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 8.5mH,  $I_{AS}$  = 11.5A,  $V_{DD}$  = 50V,  $R_{G}$  = 25 $\!\Omega$ , Starting  $T_{J}$  = 25 $^{\circ}C$
- 3.  $I_{SD} \le 11.5 A$ , di/dt  $\le 200 A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25^{\circ}C$
- 4. Essentially Independent of Operating Temperature Typical Characteristics

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

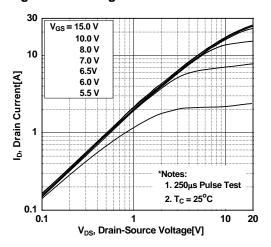


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

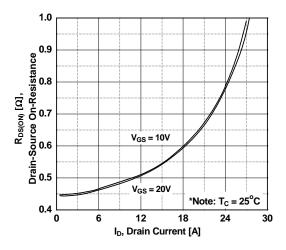


Figure 5. Capacitance Characteristics

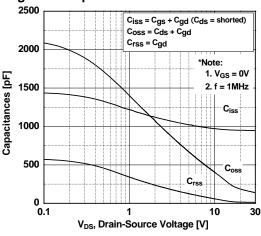


Figure 2. Transfer Characteristics

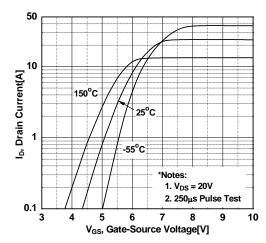


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

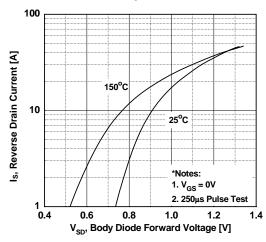
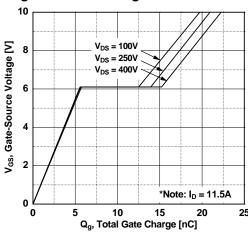


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

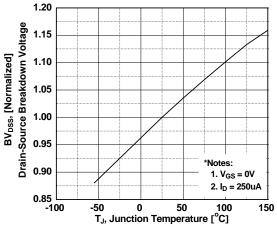


Figure 9. Maximum Safe Operating Area

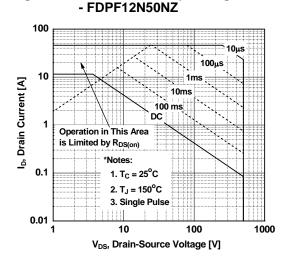


Figure 8. On-Resistance Variation vs. Temperature

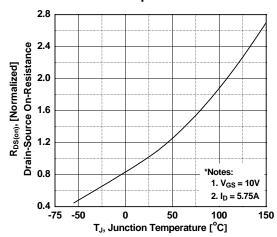


Figure 10.Maximum Safe Operating Area - FDP12N50NZ

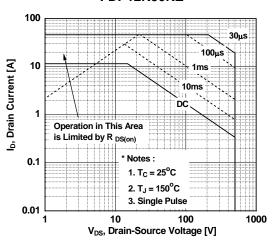
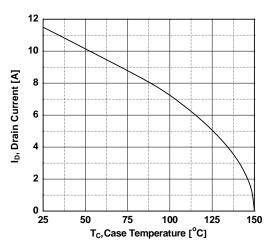


Figure 11. Maximum Drain Current vs. Case Temperature



## Typical Performance Characteristics (Continued)

Figure 12. Transient Thermal Response Curve - FDP12N50NZ

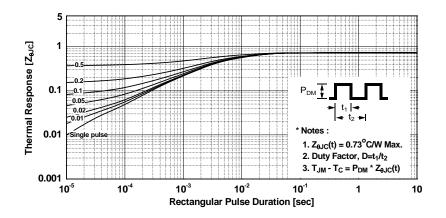
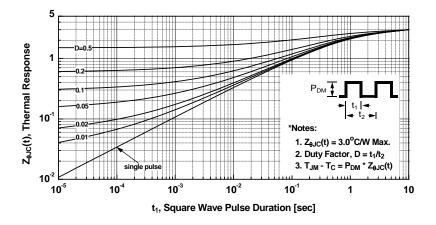
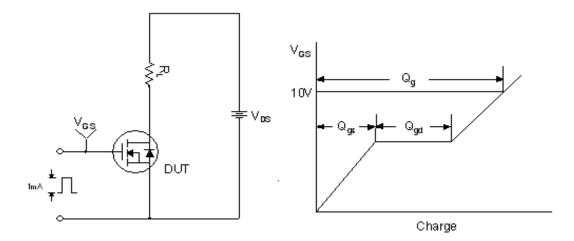


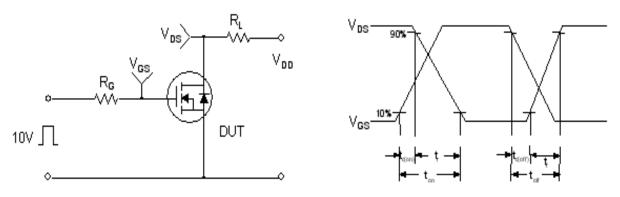
Figure 13. Transient Thermal Response Curve - FDPF12N50NZ



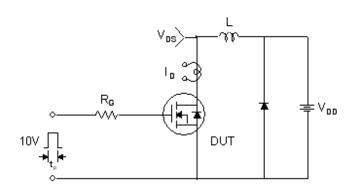
## **Gate Charge Test Circuit & Waveform**

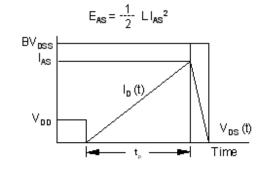


## **Resistive Switching Test Circuit & Waveforms**

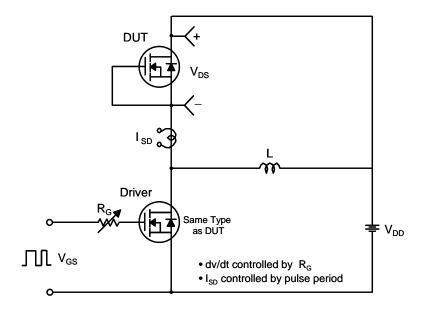


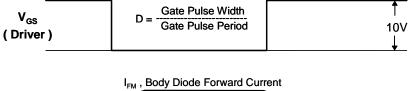
## **Unclamped Inductive Switching Test Circuit & Waveforms**

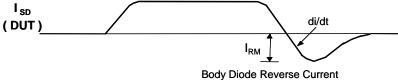


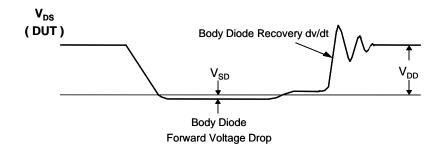


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



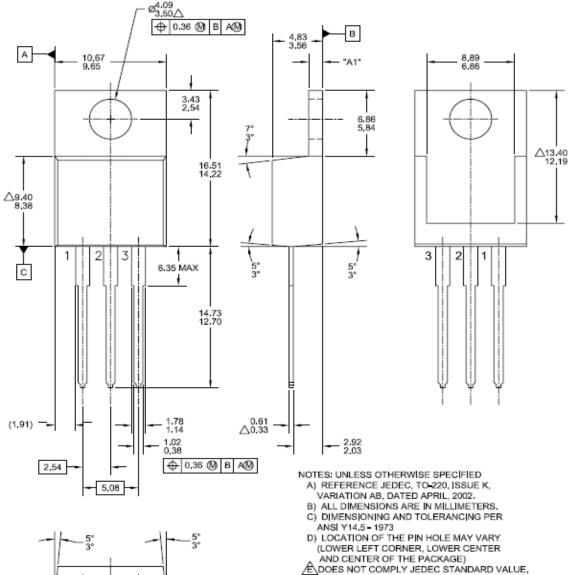






## **Mechanical Dimensions**

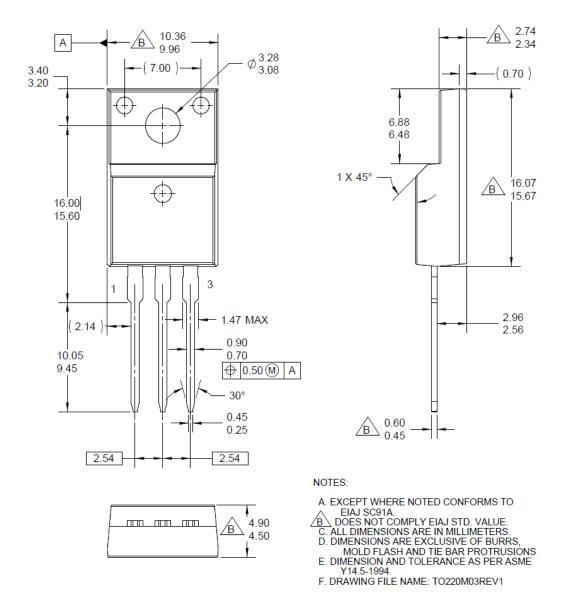
# TO-220



- F) "A1" DIMENSIONS REPRESENT LIKE BELOW: SINGLE GAUGE = 0.51 - 0.61
- DUAL GAUGE = 1.14 1.40 G) DRAWING FILE NAME: TO220B03REV6

## Package Dimensions (Continued)

# TO-220F



\* Front/Back Side Isolation Voltage: 2500V

**Dimensions in Millimeters** 





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